

MITSUBISHI LSTTL_s M74LS197P

PRESETTABLE 4-BIT BINARY COUNTER/LATCH

DESCRIPTION

The M74LS197P is a semiconductor integrated circuit containing an asynchronous hexadecimal (4-bit binary) counter function with direct reset and preset inputs.

FEATURES

- Direct reset input and asynchronous preset input provided
- Usable independently as binary and octal counter
- High-speed counting ($f_{max} = 80\text{MHz}$ typical)
- Wide operating temperature range ($T_a = -20 \sim +75^\circ\text{C}$)

APPLICATION

General purpose, for use in industrial and consumer equipment.

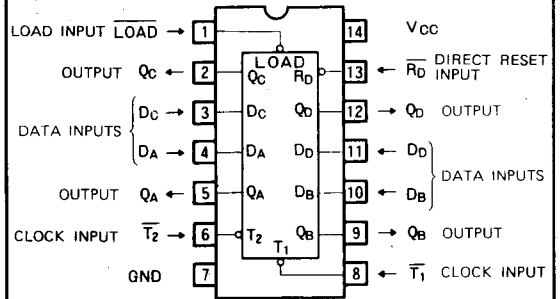
FUNCTIONAL DESCRIPTION

This device is composed of independent binary and octal counters. Clock input \overline{T}_1 and output Q_A are employed for use as a binary counter while clock input \overline{T}_2 and Q_B, Q_C and Q_D are employed for use as an octal counter. When employed as a hexadecimal counter, Q_A and \overline{T}_2 are connected and by making \overline{T}_1 the input, the count number as a 4-bit pure binary code appears in outputs Q_A, Q_B, Q_C and Q_D . Counting is performed when \overline{T}_1 and \overline{T}_2 are changed from high to low.

The counter can be preset by applying data to data inputs D_A, D_B, D_C and D_D and by setting \overline{LOAD} input low, and the D_A, D_B, D_C and D_D signals appear in Q_A, Q_B, Q_C, Q_D outputs irrespective of the \overline{T}_1 and \overline{T}_2 inputs.

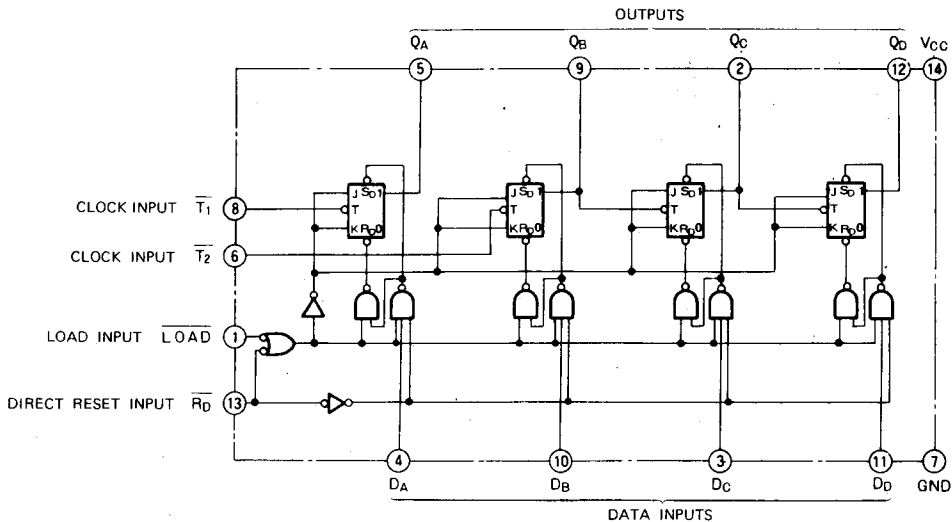
For resetting, it is possible to set $Q_A = Q_B = Q_C = Q_D =$ low by setting direct reset input \overline{RD} low irrespective of the status of the other inputs.

PIN CONFIGURATION (TOP VIEW)



Outline 14P4

BLOCK DIAGRAM



PRESETTABLE 4-BIT BINARY COUNTER/LATCH

FUNCTION TABLE (Note 1)

\overline{T}	$\overline{R_D}$	\overline{LOAD}	Q_A	Q_B	Q_C	Q_D
X	L	X	L	L	L	L
X	H	L	D_A	D_B	D_C	D_D
↓	H	H	Count			

Note 1 ↓ : Transition from high to low (negative trigger)
X : Irrelevant

Count number	Q_A	Q_B	Q_C	Q_D
0	L	L	L	L
1	H	L	L	L
2	L	H	L	L
3	H	H	L	L
4	L	L	H	L
5	H	L	H	L
6	L	H	H	L
7	H	H	H	L
8	L	L	L	H
9	H	L	L	H
10	L	H	L	H
11	H	H	L	H
12	L	L	H	H
13	H	L	H	H
14	L	H	H	H
15	H	H	H	H

(1) Valid when Q_A and \overline{T}_2 are connected and \overline{T}_1 is made the input

ABSOLUTE MAXIMUM RATINGS ($T_a = -20 \sim +75^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Limits	Unit
V_{CC}	Supply voltage		$-0.5 \sim +7$	V
V_i	Input voltage	Inputs $\overline{T}_1, \overline{T}_2$	$-0.5 \sim +5.5$	V
		Inputs $\overline{LOAD}, \overline{R_D}, D_A \sim D_D$	$-0.5 \sim +15$	
V_O	Output voltage	High-level state	$-0.5 \sim V_{CC}$	V
T_{opr}	Operating free-air ambient temperature range		$-20 \sim +75$	$^\circ\text{C}$
T_{stg}	Storage temperature range		$-65 \sim +150$	$^\circ\text{C}$

RECOMMENDED OPERATING CONDITIONS ($T_a = -20 \sim +75^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter		Limits			Unit
			Min	Typ	Max	
V_{CC}	Supply voltage		4.75	5	5.25	V
I_{OH}	High-level output current	$V_{OH} \geq 2.7\text{V}$	0		-400	μA
I_{OL}	Low-level output current	$V_{OL} \leq 0.4\text{V}$	0		4	mA
		$V_{OL} \leq 0.5\text{V}$	0		8	mA

PRESETTABLE 4-BIT BINARY COUNTER/LATCH

ELECTRICAL CHARACTERISTICS ($T_a = -20 \sim +75^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ *	Max	
V_{IH}	High-level input voltage		2			V
V_{IL}	Low-level input voltage				0.8	V
V_{IC}	Input clamp voltage	$V_{CC} = 4.75\text{V}$, $I_{IC} = -18\text{mA}$			-1.5	V
V_{OH}	High-level output voltage	$V_{CC} = 4.75\text{V}$, $V_I = 0.8\text{V}$ $V_I = 2\text{V}$, $I_{OH} = -400\mu\text{A}$	2.7	3.4		V
V_{OL}	Low-level output voltage	$V_{CC} = 4.75\text{V}$ $V_I = 0.8\text{V}$, $V_I = 2\text{V}$	$I_{OL} = 4\text{mA}$	0.25	0.4	V
			$I_{OL} = 8\text{mA}$	0.35	0.5	V
I_{IH}	High-level input current	LOAD, DA, DB, DC, DD $\overline{R_D}$, $\overline{T_1}$, $\overline{T_2}$	$V_{CC} = 5.25\text{V}$, $V_I = 2.7\text{V}$		20	μA
					40	
		LOAD, DA, DB, DC, DD $\overline{R_D}$	$V_{CC} = 5.25\text{V}$, $V_I = 5.5\text{V}$		0.2	mA
					0.1	
					0.2	
I_{IL}	Low-level input current	LOAD, DA, DB, DC, DD $\overline{R_D}$ $\overline{T_1}$ $\overline{T_2}$	$V_{CC} = 5.25\text{V}$, $V_I = 0.4\text{V}$		-0.4	mA
					-0.8	
					-2.4	
					-1.3	
I_{OS}	Short-circuit output current (note 2)	$V_{CC} = 5.25\text{V}$, $V_O = 0\text{V}$	-20		-100	mA
I_{CC}	Supply current	$V_{CC} = 5.25\text{V}$ (Note 3)		16	27	mA

* : All typical values are at $V_{CC} = 5\text{V}$, $T_a = 25^\circ\text{C}$.

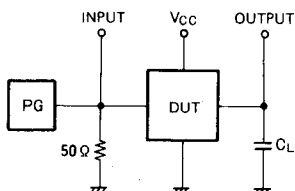
Note 2: All measurements should be done quickly and not more than one output should be shorted at a time.

Note 3: I_{CC} is measured with all inputs at 0V.

SWITCHING CHARACTERISTICS ($V_{CC} = 5\text{V}$, $T_a = 25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
f_{max}	Maximum clock frequency ($\overline{T_1}$)	$C_L = 15\text{pF}$ (Note 4)	30	80		MHz
f_{max}	Maximum clock frequency ($\overline{T_2}$)			35		MHz
t_{PLH}	Low-to-high-level, high-to-low-level output propagation time, from input $\overline{T_1}$ to output QA			6	15	ns
t_{PHL}	Low-to-high-level, high-to-low-level output propagation time, from input $\overline{T_1}$ to output QB			7	21	ns
t_{PLH}	Low-to-high-level, high-to-low-level output propagation time, from input $\overline{T_2}$ to output QA			8	19	ns
t_{PHL}	Low-to-high-level, high-to-low-level output propagation time, from input $\overline{T_2}$ to output QB			8	35	ns
t_{PLH}	Low-to-high-level, high-to-low-level output propagation time, from input $\overline{T_2}$ to output QC			15	51	ns
t_{PHL}	Low-to-high-level, high-to-low-level output propagation time, from input $\overline{T_2}$ to output QD			15	63	ns
t_{PLH}	Low-to-high-level, high-to-low-level output propagation time, from input $\overline{T_2}$ to output QD			22	78	ns
t_{PHL}	Low-to-high-level, high-to-low-level output propagation time, from input $\overline{T_2}$ to output QD			24	95	ns
t_{PLH}	Low-to-high-level, high-to-low-level output propagation time, from inputs DA, DB, DC, DD to outputs QA, QB, QC, QD			8	27	ns
t_{PHL}	Low-to-high-level, high-to-low-level output propagation time, from inputs DA, DB, DC, DD to outputs QA, QB, QC, QD			10	44	ns
t_{PLH}	Low-to-high-level output propagation time, from input LOAD to outputs QA, QB, QC, QD			13	39	ns
t_{PHL}	Low-to-high-level output propagation time, from input LOAD to outputs QA, QB, QC, QD			10	45	ns
t_{PHL}	High-to-low-level output propagation time, from input $\overline{R_D}$ to outputs QA, QB, QC, QD		13	51	ns	

Note 4: Measurement circuit



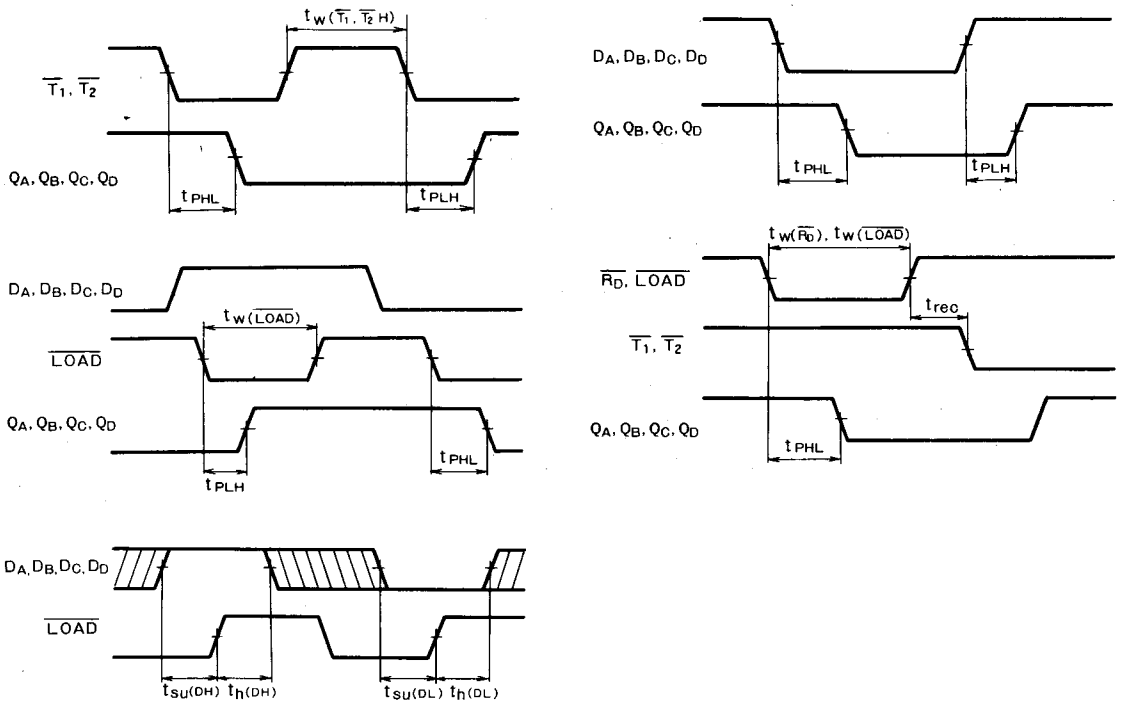
- (1) The pulse generator (PG) has the following characteristics:
PRR = 1MHz, $t_r = 6\text{ns}$, $t_f = 6\text{ns}$, $t_w = 500\text{ns}$,
 $V_p = 3V_{p-p}$, $Z_o = 50\Omega$.
- (2) C_L includes probe and jig capacitance

PRESETTABLE 4-BIT BINARY COUNTER/LATCH

TIMING REQUIREMENTS ($V_{CC} = 5 V$, $T_a = 25^\circ C$, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
$t_w(\overline{T_1H})$	Clock input $\overline{T_1}$ high pulse width		20	5		ns
$t_w(\overline{T_2H})$	Clock input $\overline{T_2}$ high pulse width		30	14		ns
$t_w(\overline{LOAD})$	Load \overline{LOAD} input pulse width		20	8		ns
$t_w(\overline{RD})$	Direct reset \overline{RD} pulse width		15	4		ns
$t_{su}(DL)$	Setup time $D_A \sim D_D$ low to \overline{LOAD}		15	3		ns
$t_{su}(DH)$	Setup time $D_A \sim D_D$ high to \overline{LOAD}		10	0		ns
$t_h(DL)$	Hold time $D_A \sim D_D$ low to \overline{LOAD}		6	0		ns
$t_h(DH)$	Hold time $D_A \sim D_D$ high to \overline{LOAD}		3	-1		ns
$t_{rec}(\overline{LOAD})$	Recovery time \overline{LOAD} to \overline{T}		30	7		ns
$t_{rec}(\overline{RD})$	Recovery time \overline{RD} to \overline{T}		30	7		ns

TIMING DIAGRAM (Reference level = 1.3V)

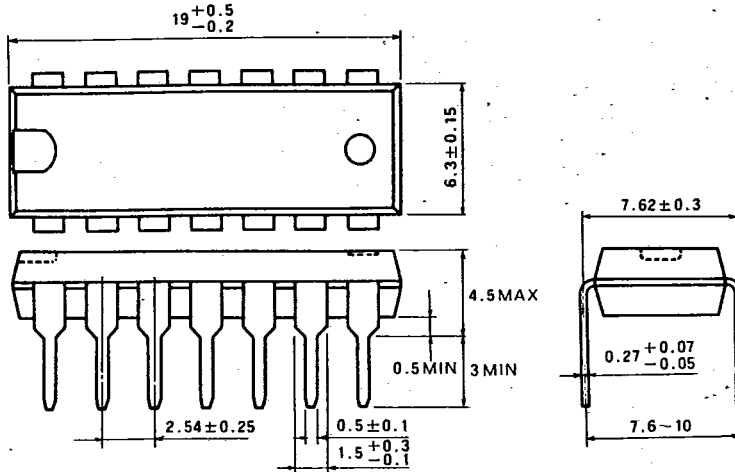


Note 5: The shaded areas indicate when the input is permitted to change for predictable output performance.

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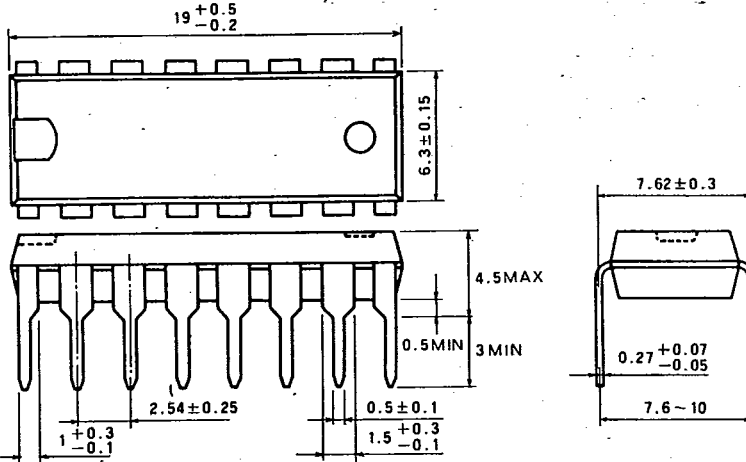
TYPE 14P4 14-PIN MOLDED PLASTIC DIL

Dimension in mm



TYPE 16P4 16-PIN MOLDED PLASTIC DIL

Dimension in mm



TYPE 20P4 20-PIN MOLDED PLASTIC DIL

Dimension in mm

